


<b>Search Notes</b> 	<b>Application/Control No.</b> 10582128	<b>Applicant(s)/Patent Under Reexamination</b> MORIMURA ET AL.
	<b>Examiner</b> SHEELA C CHAWAN	<b>Art Unit</b> 2624

### SEARCHED

Class	Subclass	Date	Examiner
382	124,127,115,116,125,126,299	6/28/09	SCC
702	104 , 130, 100	6/28/09	SCC
340	5.83, 5.83,	6/28/09	SCC
438	48, 50	6/28/09	SCC
356	71,	6/28/09	SCC
307	125,	6/28/09	SCC
257	414, 415, 416, 417,	6/28/09	SCC
178	18.05	6/28/09	SCC
345	161	6/28/09	SCC
341	33	6/28/09	SCC
200	343	6/28/09	SCC
250	556	6/28/09	SCC
382	124,125	6/28/09	SCC
702	104	6/28/09	SCC
438	48	6/28/09	SCC
340	5.83	6/28/09	SCC
ABOVE SEARCH UP- DATE		6/28/09	SCC

### SEARCH NOTES

Search Notes	Date	Examiner
SEARCH EAST AND OTHER DATA BASE, SEE THE SEARCH HISTORY,	6/28/09	SCC
SEARCH INVENTOR NAME	6/28/09	SCC
382/124,127,115,116,125,126,299.CCLS. US-PATENT TEXT SEARCH ONLY.	6/28/09	SCC
340/5.53,5.83.ccls. "	6/28/09	SCC
702/104,130.ccls. "	6/28/09	SCC
348/48, 50.CCLS. "	6/28/09	SCC
INTERFERENCE SEARCH.	6/28/09	SCC
SEARCH IEEE OR INSPEC DATA BASE.	6/28/09	SCC
SEARCH UP-DATE	6/28/09	SCC

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**SEARCH NOTES**

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
DISCUS WITH SAMIR AHMED SPE 2624	5/6/09	SCC

**INTERFERENCE SEARCH**

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	124, 125	6/28/09	SCC
702	104	6/28/09	SCC
340	5.83	6/28/09	SCC
438	48	6/28/09	SCC

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